


<b>Search Notes</b>  	<b>Application/Control No.</b>  10527186	<b>Applicant(s)/Patent Under Reexamination</b>  TOMIYAMA ET AL.
	<b>Examiner</b>  TAN X DINH	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
369	282	5/07/08	T.D
369	289.1 - 290.1	5/07/08	T.D
720	721 - 724	5/07/08	T.D

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (see search history printout)	5/07/08	T.D

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner